## Notice of References Cited Application/Control No. O9/828,575 Applicant(s)/Patent Under Reexamination SCHMIDT ET AL. Examiner Hae Moon Hyeon Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	Α	US-6371793	04-2002	Doorhy et al.	439/404
	В	US-			
	С	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	н	US-			
	1	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
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## **NON-PATENT DOCUMENTS**

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